

## Notice of R ferenc s Cit d

Application/Control I

Applicant(s)/Patent Under Reexamination FIGIEL ET AL.

Examiner Thao T. Tran Art Unit 1711

Page 1 of 1

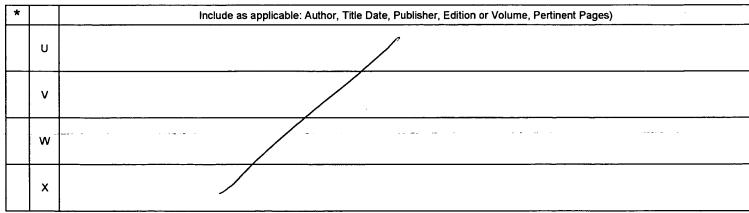
## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,716,441	02-1998	Nguyen et al.	106/207.1
	В	US-6,280,515	08-2001	Lydzinski et al.	106/122
	С	US-6,379,447	04-2002	Eden et al.	106/205.01
	D	US-6,387,474	05-2002	Richards, David W.	428/204
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	_	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**



\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.